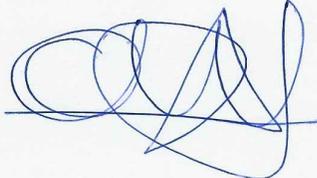


Test Report Summary

No E-18-I-027-FL

PRIME Certification Tests Cases for Base Nodes

EQUIPMENT UNDER TEST	Single-phase base node (PRIME chipset)
MODEL/FW VERSION	Base Node-EK / B14.03.01
CERTIFICATION SCOPE¹	PHY, MAC and Convergence layers. Backwards Compatibility and Security procedures are out of the scope of this certification.
MANUFACTURER	Microchip Technology Inc.
APPLICANT	Alfredo Sanz
DATE OF RECEPTION	Torre C2 Polígono Puerta Norte A-23, 50280 Zaragoza, Spain 31 st January, 2017
PRIME SPECIFICATION VERSION/TEST CASE VERSION	PRIME-Specification v1.4 Rev.1 / PRIME Certification BN Tests Cases v3.6
DATE OF EXECUTION	From February 21 st till March 08 th , 2018
DATE OF ISSUE OF REPORT	Brussels, June 11 th , 2018

Responsible for tests	Head of Laboratory	PRIME Alliance Vice President
		
Fernando Lobo	Juan Ignacio Sánchez	Oscar Márquez

* This test report summary is granted on account of tests made at location of DNVGL Services Spain SL in Madrid, Spain.
 * The results of the present report apply only to the samples tested and the moment and conditions under which the measurements were performed.
 * The complete results, including remarks and limitations, are laid down in our complete test report no. E-18-I-026-FL which can be obtained at DNVGL Services Spain SL. The certificate and the test report are indivisible.
 * The test report summary is issued by PRIME Alliance. It shall not be reproduced, in total or in part and in whatever way, without written permission of DNVGL Services Spain SL.

¹ IMPORTANT: Remarks apply to the implementation of this function. See complete test report no. E-18-I-026-FL (ANNEX I) for full details.